

5 kV rms Signal Isolated High Speed CAN Transceiver with Bus Protection

Data Sheet ADM3054

FEATURES

5 kV rms signal isolated CAN transceiver 5 V or 3.3 V operation on V_{DD1}

5 V operation on V_{DD2}

 V_{DD2SENSE} to detect loss of power on V_{DD2}

Complies with ISO 11898 standard

High speed data rates of up to 1 Mbps

Short-circuit protection on CANH and CANL against shorts to

power/ground in 24 V systems

Unpowered nodes do not disturb the bus

Connect 110 or more nodes on the bus

Thermal shutdown protection

High common-mode transient immunity: >25 kV/µs

Safety and regulatory approvals

UL recognition

5000 V rms for 1 minute per UL 1577

VDE Certificates of Conformity

DIN V VDE V 0884-10 (VDE V 0884-10): 2006-12

 $V_{IORM} = 846 V peak$

Industrial operating temperature range: -40°C to +125°C

Wide-body, 16-lead SOIC package Qualified for automotive applications

APPLICATIONS

CAN data buses Industrial field networks

GENERAL DESCRIPTION

The ADM3054 is a 5 kV rms signal isolated controller area network (CAN) physical layer transceiver. The ADM3054 complies with the ISO 11898 standard.

The device employs Analog Devices, Inc., iCoupler* technology to combine a 3-channel isolator and a CAN transceiver into a single package. The logic side of the device is powered with a single 3.3 V or 5 V supply on $V_{\rm DD1}$ and the bus side uses a single 5 V supply on $V_{\rm DD2}$ only. Loss of power on the bus side ($V_{\rm DD2}$) can be detected by an integrated $V_{\rm DD2SENSE}$ signal.

The ADM3054 creates an isolated interface between the CAN protocol controller and the physical layer bus. It is capable of running at data rates of up to 1 Mbps.

The device has integrated protection on the bus pins, CANH and CANL against shorts to power/ground in 24 V systems.

The device has current-limiting and thermal shutdown features to protect against output short circuits and situations where the bus might be shorted to ground or power terminals. The part is fully specified over the industrial temperature range and is available in a 16-lead, wide-body SOIC package.

FUNCTIONAL BLOCK DIAGRAM

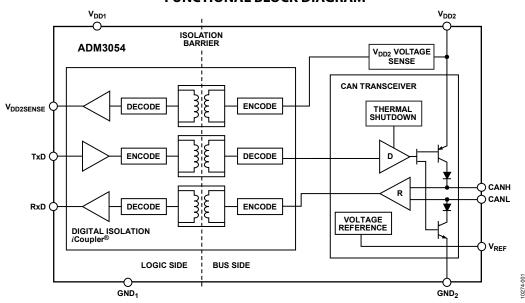


Figure 1

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REVISION HISTORY
3/2017—Rev. C to Rev. D
Change to Tracking Resistance (Comparative Tracking Index)
Parameter, Table 45
Change to ≤300 V rms Parameter, Table 5 and ≤400 V rms
Parameter, Table 5
1/2017—Rev. B to Rev. C
Change to Isolation Group Parameter, Table 45
Deleted Endnote 3, Ordering Guide; Renumbered Sequentially 20
9/2013—Rev. A to Rev. B
Changes to Features Section
Changes to Ordering Guide
Added Automotive Products Section

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Changes to Features Section1

Changed Regulatory Information (Pending) Section to

10/2011—Revision 0: Initial Version

12/2012—Rev. 0 to Rev. A

SPECIFICATIONS

Each voltage is relative to its respective ground, $3.0~V \le V_{DD1} \le 5.5~V$, $T_A = -40^{\circ}C$ to $+125^{\circ}C$, $4.75~V \le V_{DD2} \le 5.25~V$, unless otherwise noted. **Table 1.**

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions/Comments
SUPPLY CURRENT						
Power Supply Current Logic Side						
TxD/RxD Data Rate 1 Mbps	I _{DD1}		2.5	3.0	mA	
Power Supply Current Bus Side	I _{DD2}					
Recessive State				10	mA	$R_L = 60 \Omega$, see Figure 28
Dominant State				75	mA	$R_L = 60 \Omega$, see Figure 28
TxD/RxD Data Rate 1 Mbps				55	mA	$R_L = 60 \Omega$, see Figure 28
DRIVER						, ,
Logic Inputs						
Input Voltage High	V _{IH}	0.7 V _{DD1}			V	TxD
Input Voltage Low	V _{IL}			0.25 V _{DD1}	V	TxD
CMOS Logic Input Currents	I _{IH} , I _{IL}			500	μΑ	TxD
Differential Outputs	IIII, III			300	μπ	
Recessive Bus Voltage	V _{CANL} , V _{CANH}	2.0		3.0	V	V_{TxD} = high, $R_L = \infty$, see Figure 22
CANH Output Voltage	VCANH VCANH	2.75		4.5	v	$V_{TxD} = Ingri, R_L = ss, see Figure 22$
CANL Output Voltage CANL Output Voltage	V _{CANL}	0.5		2.0	V	$V_{TxD} = 10W$, see Figure 22
Differential Output Voltage	V _{CANL} V _{OD}	1.5			V	$V_{TxD} = 10w$, see Figure 22 $V_{TxD} = 10w$, $R_L = 45 \Omega$, see Figure 22
Differential Output voltage				3.0		$V_{TxD} = 10W$, $R_L = 45 \Omega$, see Figure 22 $V_{TxD} = \text{high}$, $R_L = \infty$, see Figure 22
Sharet Girarit Granat GANIII	V _{OD}	-500		+50	mV	
Short-Circuit Current, CANH	Isccanh		100	-200	mA	$V_{CANH} = -5 V$
Cl C CANII	I _{SCCANH}		-100	200	mA	$V_{CANH} = -36 V$
Short-Circuit Current, CANL	Isccanl			200	mA	$V_{CANL} = 36 V$
RECEIVER						
Differential Inputs						
Differential Input Voltage Recessive	V _{IDR}	-1.0		+0.5	V	$-2 \text{ V} < \text{V}_{\text{CANL}}, \text{V}_{\text{CANH}} < 7 \text{ V},$ see Figure 24, $\text{C}_{\text{L}} = 15 \text{ pF}$
		-1.0		+0.4	V	$-7 \text{ V} < V_{CANL}$, $V_{CANH} < 12 \text{ V}$, see Figure 24, $C_L = 15 \text{ pF}$
Differential Input Voltage Dominant	V_{IDD}	0.9		5.0	V	$-2 \text{ V} < \text{V}_{\text{CANL}}, \text{V}_{\text{CANH}} < 7 \text{ V},$ see Figure 24, $\text{C}_{\text{L}} = 15 \text{ pF}$
		1.0		5.0	V	$-7 \text{ V} < V_{CANL}$, $V_{CANH} < 12 \text{ V}$, see Figure 24, $C_L = 15 \text{ pF}$
Input Voltage Hysteresis	V _{HYS}		150		mV	See Figure 25
CANH, CANL Input Resistance	Rin	5	.55	25	kΩ	550.194.6.25
Differential Input Resistance	R _{DIFF}	20		100	kΩ	
Logic Outputs	T T T T T T T T T T T T T T T T T T T	20		100	1422	
Output Voltage Low	V _{OL}		0.2	0.4	٧	I _{ΟυΤ} = 1.5 mA
Output Voltage Low Output Voltage High	Vol	V _{DD1} - 0.3	V _{DD1} – 0.2	0.4	V	$I_{OUT} = -1.5 \text{ mA}$
Short-Circuit Current		7	VDD1 0.2	85	mA	$V_{OUT} = GND_1 \text{ or } V_{DD1}$
VOLTAGE REFERENCE	los	'		0.5	111/4	וטט אייט ועטויי דעט אייט ויטטיי
Reference Output Voltage	\/	2 025		2 025	\ \ \	
	V _{REF}	2.025		3.025	V	$ I_{REF} = 50 \mu\text{A} $
V _{DD2} VOLTAGE SENSE			0.2	0.4	.,	154
V _{DD2SENSE} Output Voltage Low	V _{OL}	.,	0.2	0.4	V	$I_{OSENSE} = 1.5 \text{ mA}$
V _{DD2SENSE} Output Voltage High	V _{OH}	$V_{DD1} - 0.3$	$V_{\text{DD1}}-0.2$		V	$I_{OSENSE} = -1.5 \text{ mA}$
Bus Voltage Sense Threshold Voltage	V _{TH(SENSE)}	2.0		2.5	V	V _{DD2}
COMMON-MODE TRANSIENT IMMUNITY ¹		25			kV/μs	$V_{CM} = 1$ kV, transient, magnitude = 800 V

 $^{^1}$ CM is the maximum common-mode voltage slew rate that can be sustained while maintaining specification compliant operation. V_{CM} is the common-mode potential difference between the logic and bus sides. The transient magnitude is the range over which the common mode is slewed. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

TIMING SPECIFICATIONS

Each voltage is relative to its respective ground, 3.0 V \leq V_{DD1} \leq 5.5 V. T_A = -40° C to $+125^{\circ}$ C, 4.75 V \leq V_{DD2} \leq 5.25 V, unless otherwise noted.

Table 2.

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions/Comments
DRIVER						
Maximum Data Rate		1			Mbps	
Propagation Delay TxD On to Bus Active	t _{onTxD}			90	ns	$R_L = 60~\Omega$, $C_L = 100~pF$, see Figure 23 and Figure 27
Propagation Delay TxD Off to Bus Inactive	t _{offTxD}			120	ns	$R_L = 60~\Omega$, $C_L = 100~pF$, see Figure 23 and Figure 27
RECEIVER						
Propagation Delay TxD On to Receiver Active	t _{onRxD}			200	ns	$R_L = 60 \Omega$, $C_L = 100 pF$, see Figure 23 and Figure 27
Propagation Delay TxD Off to Receiver Inactive	t _{offRxD}			250	ns	$R_L = 60~\Omega, C_L = 100~pF$, see Figure 23 and Figure 27
POWER-UP						
Enable Time, VDD2 High to VDD2SENSE Low	t _{SE}			300	μs	See Figure 26
Disable Time, VDD2 Low to VDD2SENSE High	t _{SD}			10	ms	See Figure 26

REGULATORY INFORMATION

Table 3. ADM3054 Approvals

Organization	Approval Type	Notes
UL	Recognized under the component recognition program of Underwriters Laboratories, Inc.	In accordance with UL 1577, each ADM3054 is proof tested by applying an insulation test voltage ≥ 6000 V rms for 1 second
VDE	Certified according to DIN V VDE V 0884-10 (VDE V 0884-10): 2006-12	In accordance with DIN V VDE V 0884-10, each ADM3054 is proof tested by applying an insulation test voltage ≥ 1590 V peak for 1 second (partial discharge detection limit = 5 pC)

INSULATION AND SAFETY-RELATED SPECIFICATIONS

Table 4.

Parameter	Symbol	Value	Unit	Test Conditions/Comments
Rated Dielectric Insulation Voltage		5000	V rms	1-minute duration
Minimum External Air Gap (External Clearance)	L(I01)	8.0	mm	Measured from input terminals to output terminals, shortest distance through air
Minimum External Tracking (Creepage)	L(102)	7.6	mm	Measured from input terminals to output terminals, shortest distance along body
Minimum Internal Gap (Internal Clearance)		0.017 min	mm	Insulation distance through insulation
Tracking Resistance (Comparative Tracking Index)	CTI	>400	V	DIN IEC 112/VDE 0303-1
Isolation Group		II		Material group (DIN VDE 0110)

VDE 0884 INSULATION CHARACTERISTICS

This isolator is suitable for reinforced electrical isolation only within the safety limit data. Maintenance of the safety data must be ensured by means of protective circuits.

Table 5.

Description	Test Conditions/Comments	Symbol	Characteristic	Unit
CLASSIFICATIONS				
Installation Classification per DIN VDE 0110 for Rated Mains Voltage				
≤150 V rms			I to IV	
≤300 V rms			I to IV	
≤400 V rms			l to III	
Climatic Classification			40/125/21	
Pollution Degree	DIN VDE 0110		2	
VOLTAGE				
Maximum Working Insulation Voltage		V _{IORM}	846	V peak
Input-to-Output Test Voltage, Method B1	$V_{IORM} \times 1.875 = V_{PR}$, 100% production tested, $t_m = 1$ sec, partial discharge < 5 pC	V_{PR}	1590	V peak
Input-to-Output Test Voltage, Method A				
After Environmental Tests, Subgroup 1	$V_{IORM} \times 1.6 = V_{PR}$, $t_m = 60$ sec, partial discharge < 5 pC	V_{PR}	1357	V peak
After Input and/or Safety Test, Subgroup 2/Subgroup 3:	$V_{IORM} \times 1.2 = V_{PR}$, $t_m = 60$ sec, partial discharge < 5 pC	V_{PR}	1018	V peak
Highest Allowable Overvoltage		V_{TR}	6000	V peak
SAFETY LIMITING VALUES				
Case Temperature		Ts	150	°C
Input Current		Is, INPUT	265	mA
Output Current		Is, output	335	mA
Insulation Resistance at T _S		Rs	>109	Ω

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25$ °C, unless otherwise noted. Each voltage is relative to its respective ground.

Table 6.

14014 01	
Parameter	Rating
V_{DD1} , V_{DD2}	−0.5 V to +6 V
Digital Input Voltage	
TxD	$-0.5 \text{ V to V}_{DD1} + 0.5 \text{ V}$
Digital Output Voltage	
RxD	$-0.5 V$ to $V_{DD1} + 0.5 V$
V_{DD2SENSE}	$-0.5 \text{ V to V}_{DD1} + 0.5 \text{ V}$
CANH, CANL	−36 V to +36 V
V_{REF}	−0.5 V to +6 V
Operating Temperature Range	-40°C to +125°C
Storage Temperature Range	−55°C to +150°C
ESD (Human Body Model)	±3.5 kV
Lead Temperature	
Soldering (10 sec)	300°C
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C
θ_{JA} Thermal Impedance	53°C/W
T _J Junction Temperature	150°C

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

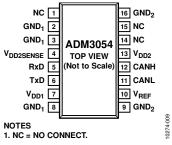


Figure 2. Pin Configuration

Table 7. Pin Function Descriptions

Pin No.	Mnemonic	Description
1	NC	No Connect. This pin remains unconnected.
2	GND₁	Ground (Logic Side).
3	GND₁	Ground (Logic Side).
4	V _{DD2SENSE}	V _{DD2} Voltage Sense. A low level on V _{DD2SENSE} indicates that power is connected on V _{DD2} . A high level on V _{DD2SENSE} indicates a loss of power on V _{DD2} .
5	RxD	Receiver Output Data.
6	TxD	Driver Input Data.
7	V _{DD1}	Power Supply (Logic Side); 3.3 V or 5 V. A decoupling capacitor to GND ₁ is required; a capacitor value between 0.01 μ F and 0.1 μ F is recommended.
8	GND ₁	Ground (Logic Side).
9	GND ₂	Ground (Bus Side).
10	V_{REF}	Reference Voltage Output.
11	CANL	Low Level CAN Voltage Input/Output.
12	CANH	High Level CAN Voltage Input/Output.
13	V_{DD2}	Power Supply (Bus Side); 5 V. A decoupling capacitor to GND ₂ is required; a capacitor value of 0.1 μF is recommended.
14	NC	No Connect. This pin remains unconnected.
15	NC	No Connect. This pin remains unconnected.
16	GND ₂	Ground (Bus Side).

TYPICAL PERFORMANCE CHARACTERISTICS

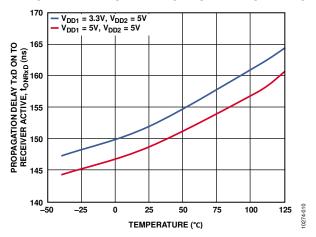


Figure 3. Propagation Delay from TxD On to Receiver Active vs. Temperature

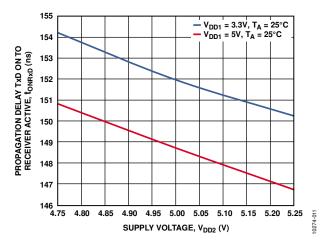


Figure 4. Propagation Delay from TxD On to Receiver Active vs. Supply Voltage, V_{DD2}

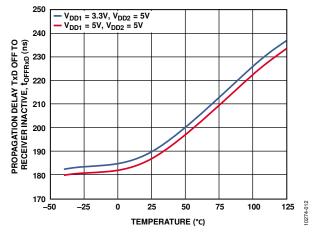


Figure 5. Propagation Delay from TxD Off to Receiver Inactive vs. Temperature

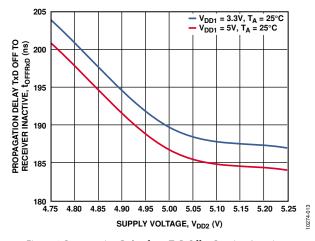


Figure 6. Propagation Delay from TxD Off to Receiver Inactive vs. Supply Voltage, V_{DD2}

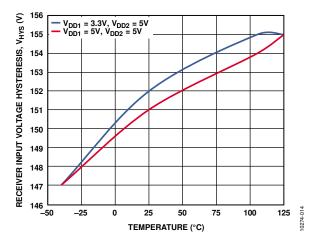


Figure 7. Receiver Input Hysteresis vs. Temperature

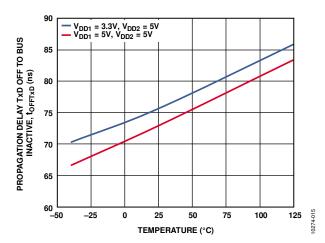


Figure 8. Propagation Delay from TxD Off to Bus Inactive vs. Temperature

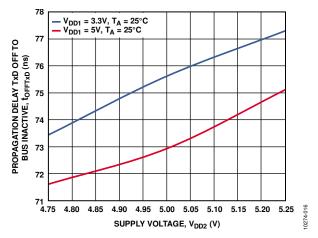


Figure 9. Propagation Delay from TxD Off to Bus Inactive vs. Supply Voltage, V_{DD2}

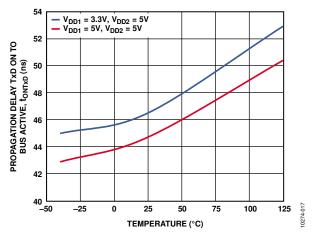


Figure 10. Propagation Delay from TxD On to Bus Active vs. Temperature

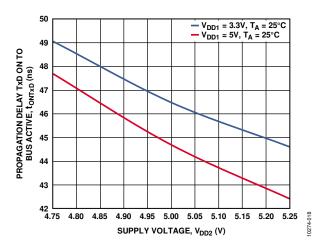


Figure 11. Propagation Delay from TxD On to Bus Active vs. Supply Voltage, V_{DD2}

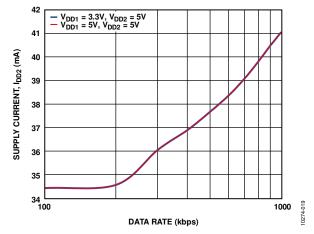


Figure 12. Supply Current (IDD2) vs. Data Rate

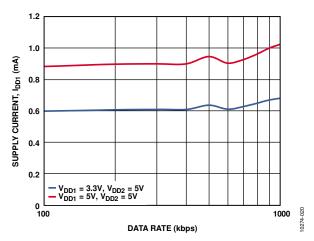


Figure 13. Supply Current (IDD1) vs. Data Rate

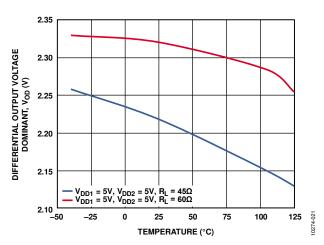


Figure 14. Driver Differential Output Voltage Dominant vs. Temperature

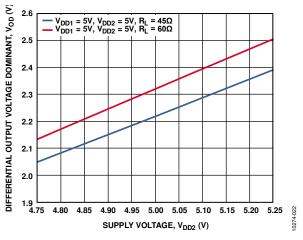


Figure 15. Driver Differential Output Voltage Dominant vs. Supply Voltage, V_{DD2}

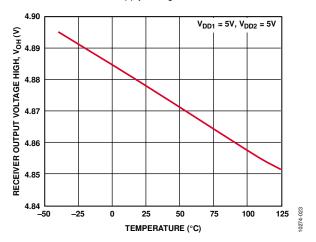


Figure 16. Receiver Output High Voltage vs. Temperature

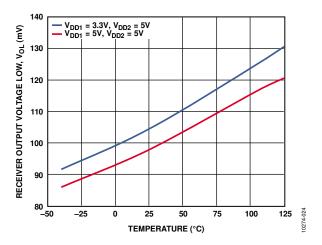


Figure 17. Receiver Output Low Voltage vs. Temperature

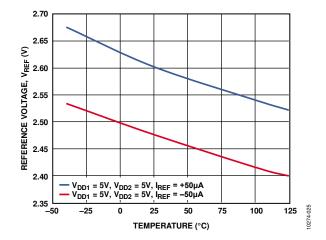


Figure 18. V_{REF} vs. Temperature

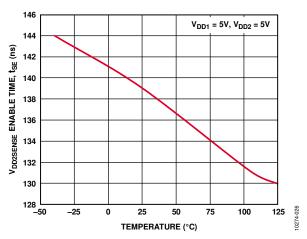


Figure 19. Enable Time, V_{DD2} High to V_{DD2SENSE} Low vs. Temperature

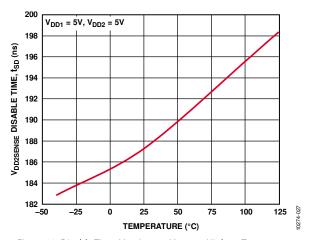


Figure 20. Disable Time, V_{DD2} Low to $V_{DD2SENSE}$ High vs. Temperature

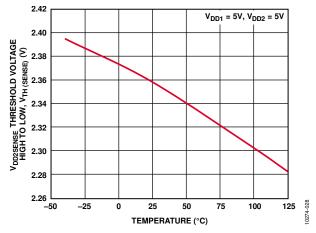


Figure 21. V_{DD2} Voltage Sense Threshold Voltage High to Low vs. Temperature

TEST CIRCUITS AND SWITCHING CHARACTERISTICS

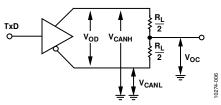


Figure 22. Driver Voltage Measurement

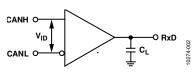


Figure 24. Receiver Voltage Measurements

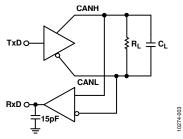


Figure 23. Switching Characteristics Measurements

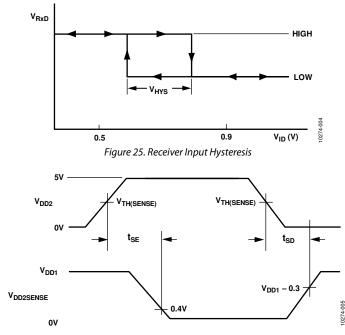


Figure 26. V_{DD2SENSE} Enable/Disable Time

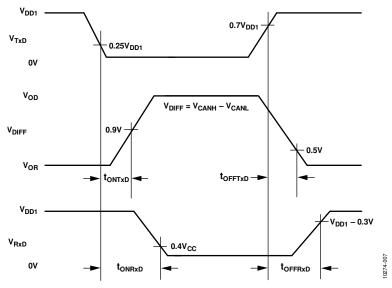


Figure 27. Driver and Receiver Propagation Delay

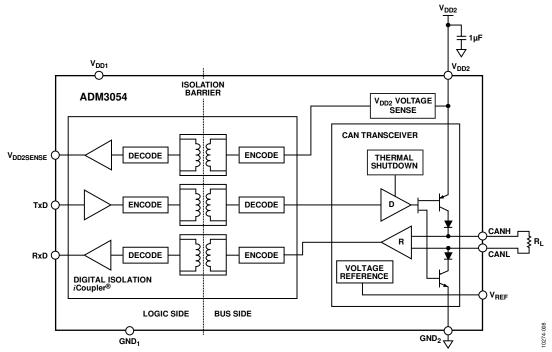


Figure 28. Supply Current Measurement Test Circuit

THEORY OF OPERATION

CAN TRANSCEIVER OPERATION

A CAN bus has two states: dominant and recessive. A dominant state is present on the bus when the differential voltage between CANH and CANL is greater than 0.9 V. A recessive state is present on the bus when the differential voltage between CANH and CANL is less than 0.5 V. During a dominant bus state, the CANH pin is high and the CANL pin is low. During a recessive bus state, both the CANH and CANL pins are in the high impedance state.

The driver drives CANH high and CANL low (dominant state) when a logic low is present on TxD. If a logic high is present on TxD, the driver outputs are placed in a high impedance state (recessive state). The driver output states are presented in Table 9.

The receiver output is low when the bus is in the dominant state and high when the bus is in the recessive state. If the differential voltage between CANH and CANL is between 0.5 V and 0.9 V, the bus state is indeterminate and the receiver output can be either high or low. The receiver output states for given inputs are listed in Table 10.

THERMAL SHUTDOWN

The ADM3054 contains thermal shutdown circuitry that protects the part from excessive power dissipation during fault conditions. Shorting the driver outputs to a low impedance source can result in high driver currents. The thermal sensing circuitry detects the increase in die temperature under this condition and disables the driver outputs. This circuitry is designed to disable the driver outputs when a junction temperature of 150°C is reached. As the device cools, the drivers reenable at a temperature of 140°C.

TRUTH TABLES

The truth tables in this section use the abbreviations listed in Table 8.

Table 8. Truth Table Abbreviations

Letter	Description
Н	High level
L	Low level
1	Indeterminate
Χ	Don't care
Z	High impedance (off)
NC	Disconnected

Table 9. Transmitting

Supply Status Input			Input	Outputs					
V_{DD1} V_{DD2}		TxD	State	CANH	CANL	V _{DD2SENSE}			
	On	On	L	Dominant	Н	L	L		
	On	On	Н	Recessive	Z	Z	L		
	On	On	Floating	Recessive	Z	Z	L		
	Off	On	Х	Recessive	Z	Z	1		
	On	Off	L	1	1	1	Н		

Table 10. Receiving

Supply Status		y Status	Inputs		Outputs	
	V_{DD1}	V _{DD2}	V _{ID} = CANH – CANL	Bus State	RxD	V _{DD2SENSE}
	On	On	≥0.9 V	Dominant	L	L
	On	On	≤0.5 V	Recessive	Н	L
	On	On	$0.5 \text{ V} < V_{ID} < 0.9 \text{ V}$	1	1	L
	On	On	Inputs open	Recessive	Н	L
	Off	On	X	Х	1	1
	On	Off	X	X	Н	Н

ELECTRICAL ISOLATION

In the ADM3054, electrical isolation is implemented on the logic side of the interface. Therefore, the device has two main sections: a digital isolation section and a transceiver section (see Figure 29). The driver input signal, which is applied to the TxD pin and referenced to the logic ground (GND1), is coupled across an isolation barrier to appear at the transceiver section referenced to the isolated ground (GND2). Similarly, the receiver input, which is referenced to the isolated ground in the transceiver section, is coupled across the isolation barrier to appear at the RxD pin referenced to the logic ground.

*i*Coupler *Technology*

The digital signals transmit across the isolation barrier using iCoupler technology. This technique uses chip scale transformer windings to couple the digital signals magnetically from one side of the barrier to the other. Digital inputs are encoded into waveforms that are capable of exciting the primary transformer winding. At the secondary winding, the induced waveforms are decoded into the binary value that was originally transmitted.

Positive and negative logic transitions at the input cause narrow (~ 1 ns) pulses to be sent to the decoder via the transformer. The decoder is bistable and is, therefore, set or reset by the pulses, indicating input logic transitions. In the absence of logic transitions at the input for more than ~ 1 μs , a periodic set of refresh pulses, indicative of the correct input state, are sent to ensure dc correctness at the output. If the decoder receives no internal pulses for more than about 5 μs , the input side is assumed to be unpowered or nonfunctional, in which case the output is forced to a default state (see Table 9).

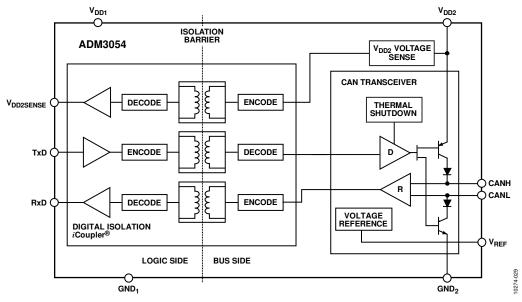


Figure 29. Digital Isolation and Transceiver Sections

MAGNETIC FIELD IMMUNITY

The limitation on the magnetic field immunity of the *i*Coupler is set by the condition in which an induced voltage in the receiving coil of the transformer is large enough to either falsely set or reset the decoder. The following analysis defines the conditions under which this may occur. The 3 V operating condition of the ADM3054 is examined because it represents the most susceptible mode of operation.

The pulses at the transformer output have an amplitude greater than 1 V. The decoder has a sensing threshold of about 0.5 V, thus establishing a 0.5 V margin in which induced voltages can be tolerated

The voltage induced across the receiving coil is given by

$$V = \left(\frac{-d\beta}{dt}\right) \sum \pi r_n^2; n = 1, 2, ..., N$$

where:

 β is the magnetic flux density (gauss). N is the number of turns in the receiving coil. r_n is the radius of the nth turn in the receiving coil (cm).

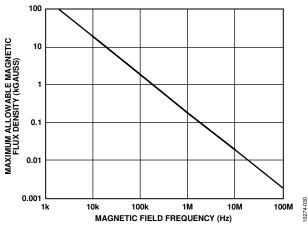


Figure 30. Maximum Allowable External Magnetic Flux Density

Given the geometry of the receiving coil and an imposed requirement that the induced voltage is, at most, 50% of the 0.5 V margin at the decoder, a maximum allowable magnetic field can be determined using Figure 30.

For example, at a magnetic field frequency of 1 MHz, the maximum allowable magnetic field of 0.2 kgauss induces a voltage of 0.25 V at the receiving coil. This is approximately 50% of the sensing threshold and does not cause a faulty output transition. Similarly, if such an event occurs during a transmitted pulse and is the worst-case polarity, it reduces the received pulse from >1.0 V to 0.75 V, still well above the 0.5 V sensing threshold of the decoder.

Figure 31 shows the magnetic flux density values in terms of more familiar quantities, such as maximum allowable current flow at given distances away from the ADM3054 transformers.

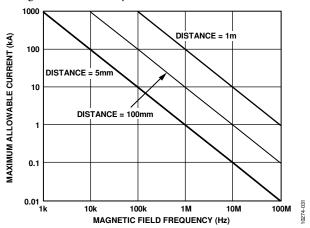


Figure 31. Maximum Allowable Current for Various Current-to-ADM3054 Spacings

With combinations of strong magnetic field and high frequency, any loops formed by printed circuit board (PCB) traces can induce error voltages large enough to trigger the thresholds of succeeding circuitry. Therefore, care is necessary in the layout of such traces to avoid this possibility.

APPLICATIONS INFORMATION

TYPICAL APPLICATIONS

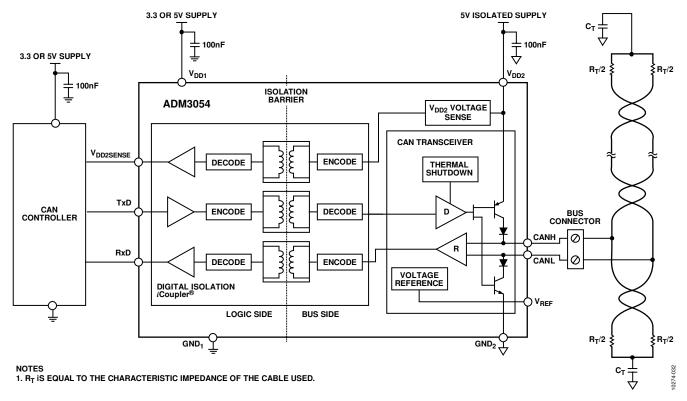


Figure 32. Typical Isolated CAN Node Using the ADM3054

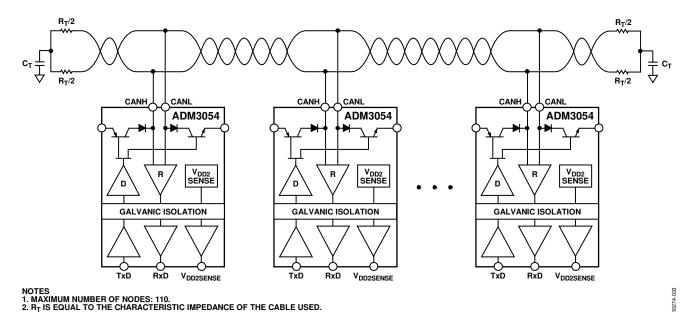
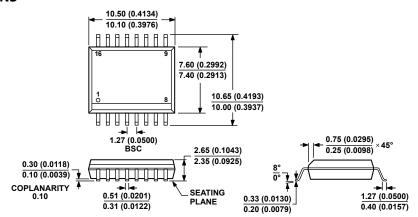


Figure 33. Typical CAN Bus Using the ADM3054

PACKAGING AND ORDERING INFORMATION

OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MS-013-AA
CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS
(IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR
REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

Figure 34. 16-Lead Standard Small Outline Package [SOIC_W] Wide Body (RW-16) Dimensions shown in millimeters and (inches)

ORDERING GUIDE

Model ^{1, 2}	Temperature Range	Package Description	Package Option ³
ADM3054BRWZ	-40°C to +125°C	16-Lead Standard Small Outline Package [SOIC_W]	RW-16
ADM3054BRWZ-RL7	-40°C to +125°C	16-Lead Standard Small Outline Package [SOIC_W]	RW-16
ADM3054WBRWZ-RL7	-40°C to +125°C	16-Lead Standard Small Outline Package [SOIC_W]	RW-16
EVAL-ADM3054EBZ		Evaluation Board	

¹ Z = RoHS Compliant Part.

AUTOMOTIVE PRODUCTS

The ADM3054W models are available with controlled manufacturing to support the quality and reliability requirements of automotive applications. Note that these automotive models may have specifications that differ from the commercial models; therefore, designers should review the Specifications section of this data sheet carefully. Only the automotive grade products shown are available for use in automotive applications. Contact your local Analog Devices account representative for specific product ordering information and to obtain the specific Automotive Reliability reports for these models.

² W = Qualified for Automotive Applications.

³ The ADM3054WBRWZ-RL7 package option is halide free.